## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:
Kazunori IWAMOTO et al.
Application No.: 09/866,600
Filed: May 30, 2001
For: STAGE APPARATUS WHICH SUPPORTS INTERFEROMETER, STAGE POSITION MEASUREMENT METHOD, PROJECTION EXPOSURE APPARATUS, PROJECTION
EXPOSURE APPARATUS MAINTENANCE
METHOD, SEMICONDUCTOR DEVICE MANUFACTURING METHOD, AND
SEMICONDUCTOR MANUFACTURING FACTORY
: Examiner: H. Nguyen
)
Group Art Unit: 2851
)
Confirmation No.: 4961
)
Allowed: October 14, 2004
)
: December 16, 2004
)
:
)

## Mail Stop Issue Fee

Commissioner for Patents
P.O. Box 1450

Alexandria, VA 22313-1450

## LETTER TRANSMITTING CORRECTED FORMAL DRAWINGS

Sir:
Transmitted herewith are two (2) formal drawing sheets, corrected Figs. 5 and 6, to be substituted for the corresponding drawing sheet currently on file in the above-identified application.

Figures 5 and 6 incorporate the changes requested by Applicants in a Request for Approval of Drawing Changes filed August 30, 2003, which were subsequently approved by the Examiner in the Notice of Allowability dated October 14, 2004.

Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should be directed to our address listed below.

Respectfully submitted,


Steven E. Warner
Registration No. 33,326

FITZPATRICK, CELLA, HARPER \& SCINTO
30 Rockefeller Plaza
New York, New York 10112-3800
Facsimile: (212) 218-2200

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